Se	arch Notes

Application/Control No.	Applicant(s)/Pater Reexamination	nt under
10/649,105	WEBB, PETER	3.
Examiner	Art Unit	
Young J. Kim	1637	

SEARCHED		
Subclass	Date	Examiner
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	INT	INTERFERENCE SEARCHED		
	Class	Subclass	Date	Examiner
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SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
Patent Databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB)	9/14/2005	YJK
See enclosed for search strategy	9/14/2005	YJK
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